

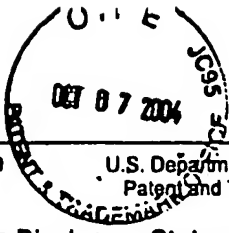
Substitute Form PTO-1449 (Modified)  <b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary)  (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 17268-004001	Application No. 10/797,497
	Applicant Hitoshi Takeda et al.		
	Filing Date March 10, 2004	Group Art Unit 2821	

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
EA	AA	20010019486	09/06/2001	Thominet	362	543	
	AB						
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	AD						
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	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation Abstract	
							Yes	No
EA	AL	2002-231014	08/16/2002	Japan			X	
	AM							
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	AQ	
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	AS	
	AT	

Examiner Signature <i>Ephrem A. Lence</i>	Date Considered 5-11-05
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

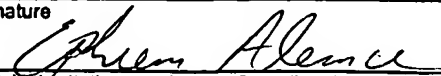


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U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
EA	AA	20040179367	09/16/2004	Takeda et al.	362	466	
EA	AB	20040179368	09/16/2004	Takeda et al.	362	466	
EA	AC	20040179366	09/16/2004	Takeda et al.	362	464	
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Examiner Signature 	Date Considered <b>5-18-05</b>
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